

Proof-of-principle experiment for single-shot transverse phase space measurement

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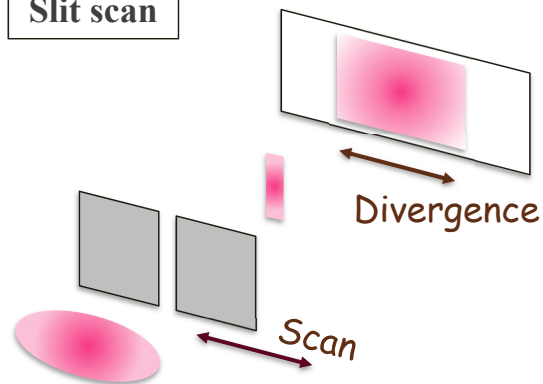
Content

- Introduction of new method
- Demonstration using beam dynamics simulation
- Limiting factors
- Applications
- Experimental demonstration



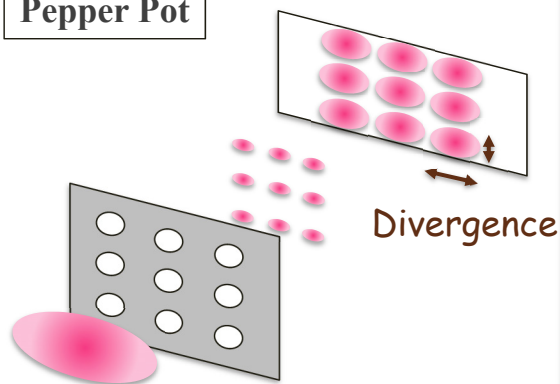
How do we measure transverse phase space?

Slit scan



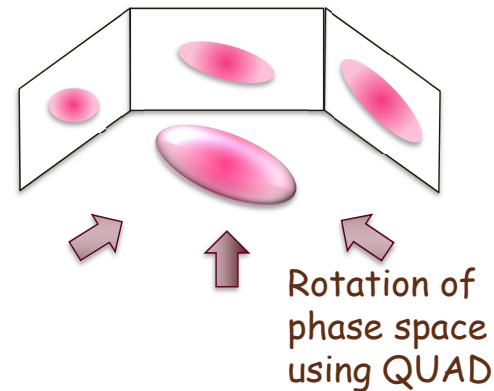
- ☺ Full image of phase space
- ☹ Averaged image only
- ☹ Long data taking time
- ☹ Inadequate for high E / low divergence

Pepper Pot



- ☹ Partial image of phase space
- ☺ Single shot / average
- ☺ Short data taking time
- ☹ Inadequate for high E / low divergence

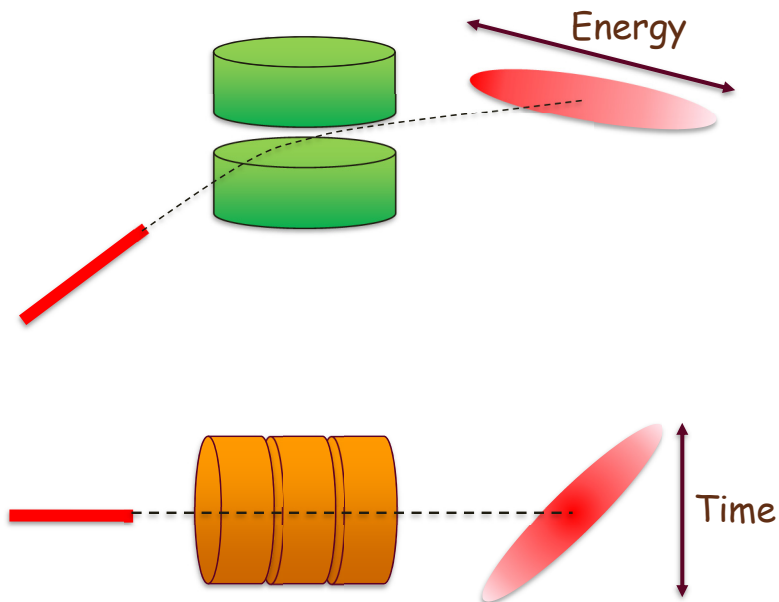
Tomography



- ☺ Full image of phase space
- ☹ Averaged image only
- ☹ Long data taking time
- ☺ Adequate for high E / low divergence

Can we use PROJECTION scheme for transverse phase space?

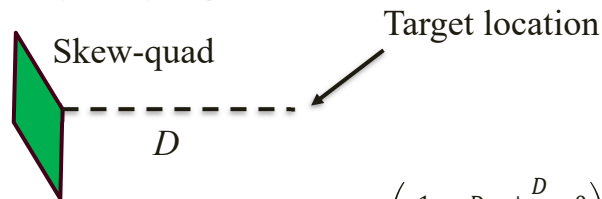
We already do projection of an interested coordinate to an easy-to-measure coordinate!!!



How to project (x, x') to (x, y) ?

Step1

We need x-y coupling



$$\begin{pmatrix} 1 & D & 0 & 0 \\ 0 & 1 & 0 & 0 \\ 0 & 0 & 1 & D \\ 0 & 0 & 0 & 1 \end{pmatrix} \begin{pmatrix} 1 & 0 & 0 & 0 \\ 0 & 1 & \pm \frac{1}{f} & 0 \\ 0 & 0 & 1 & 0 \\ \pm \frac{1}{f} & 0 & 0 & 1 \end{pmatrix} = \begin{pmatrix} 1 & D & \pm \frac{D}{f} & 0 \\ 0 & 1 & \pm \frac{1}{f} & 0 \\ \pm \frac{D}{f} & 0 & 1 & D \\ \pm \frac{1}{f} & 0 & 0 & 1 \end{pmatrix}$$



$$x_f = x_0 + D x'_0 \pm \frac{D}{f} y_0$$

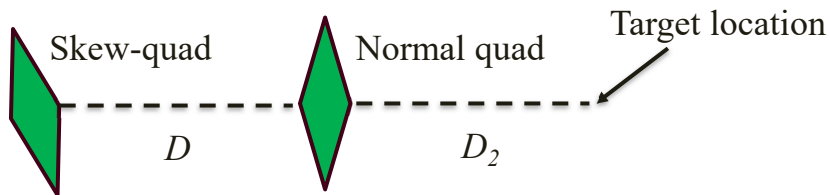
$$y_f = \pm \frac{D}{f} x_0 + y_0 + D y'_0$$



Projection of transverse phase space

Step2

We don't want x-x relation



$$\begin{pmatrix} 0 & D_2 & 0 & 0 \\ -\frac{1}{D_2} & 1 & 0 & 0 \\ 0 & 0 & 2 & D_2 \\ 0 & 0 & \frac{1}{D_2} & 1 \end{pmatrix} \begin{pmatrix} 1 & D & \pm\frac{D}{f} & 0 \\ 0 & 1 & \pm\frac{1}{f} & 0 \\ \pm\frac{D}{f} & 0 & 1 & D \\ \pm\frac{1}{f} & 0 & 0 & 1 \end{pmatrix} = \begin{pmatrix} 0 & D_2 & \pm\frac{D_2}{f} & 0 \\ -\frac{1}{D_2} & 1 - \frac{D}{D_2} & \pm\frac{1}{f}\left(1 - \frac{D}{D_2}\right) & 0 \\ \pm\frac{2D + D_2}{f} & 0 & 2 & 2D + D_2 \\ \pm\frac{1}{f}\left(1 + \frac{D}{D_2}\right) & 0 & \frac{1}{D_2} & 1 + \frac{D}{D_2} \end{pmatrix}$$

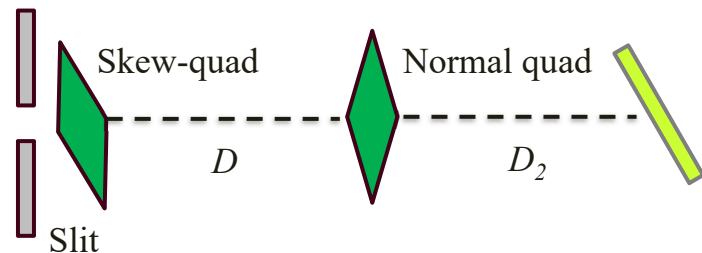
→

$$x_f = (D_2)x'_0 \pm \frac{D_2}{f} y_0$$

$$y_f = \pm \frac{2D + D_2}{f} x_0 + 2y_0 + (2D + D_2)y'_0$$

Step3

We don't want vertical contribution



$$x_f \cong (D_2)x'_0$$

$$y_f \cong \pm \frac{2D + D_2}{f} x_0$$

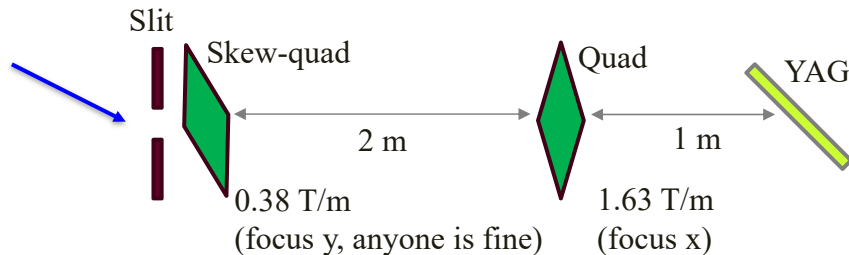
when $\sigma_{x'_0} \times f_{SQ} \gg \sigma_{y_0}$

$$\left(\frac{\sigma_{x_0}}{f_{SQ}}\right)^2 \gg \sigma_{y'_0}^2 + \frac{4\sigma_{y_0}^2}{(2D + D_2)^2} + \frac{4\sigma_{yy'}}{(2D + D_2)}$$



Test with realistic quadrupoles

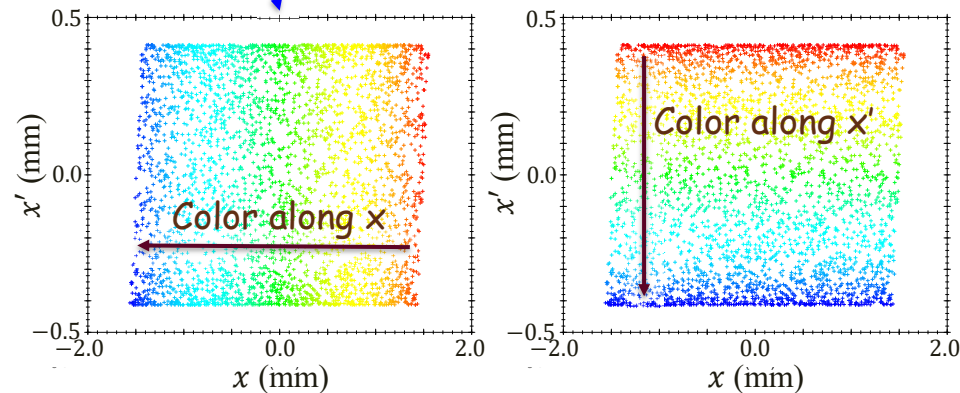
Set this configuration
in beam dynamics code



Transfer matrix

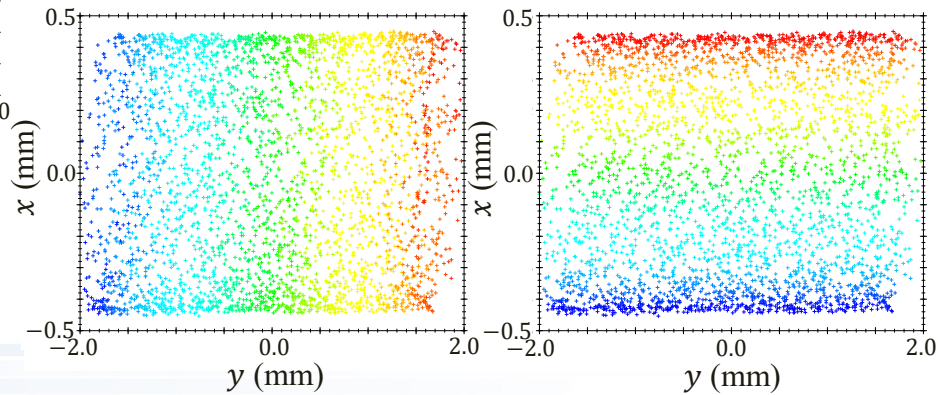
$$\begin{pmatrix} 0.00 & \mathbf{1.05} & -0.24 & -0.04 \\ -0.95 & -1.14 & 0.23 & 0.03 \\ \mathbf{-1.20} & -0.18 & 2.04 & 5.62 \\ -0.69 & -0.10 & 0.99 & 3.21 \end{pmatrix}$$

Send artificial beam
to the beamline

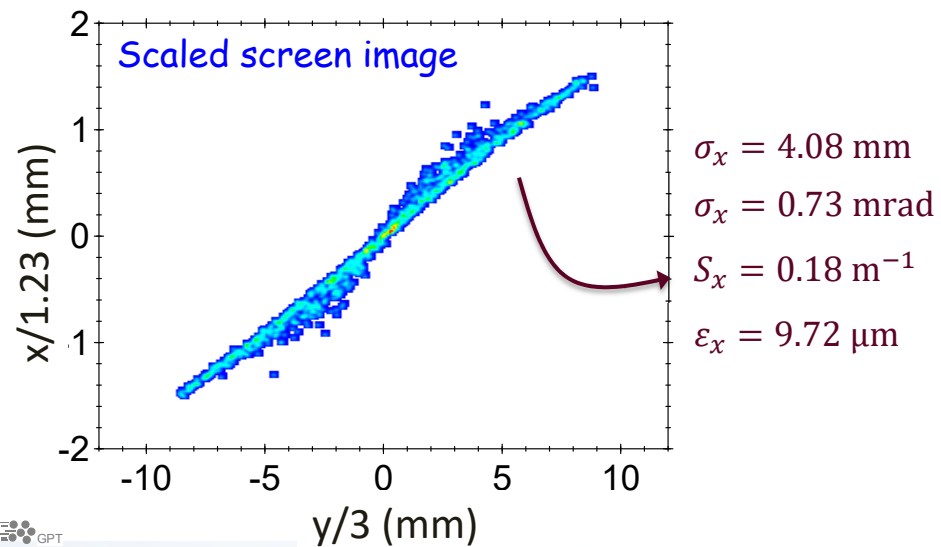
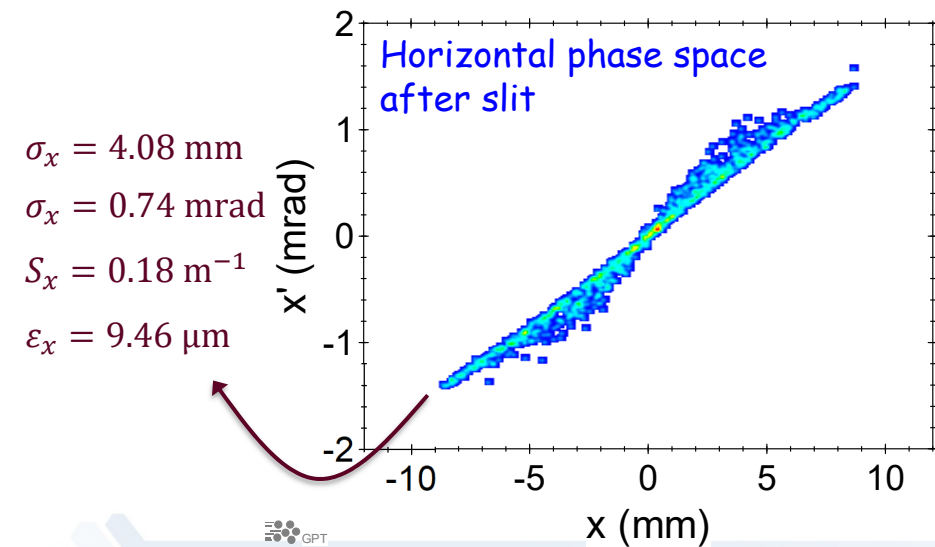
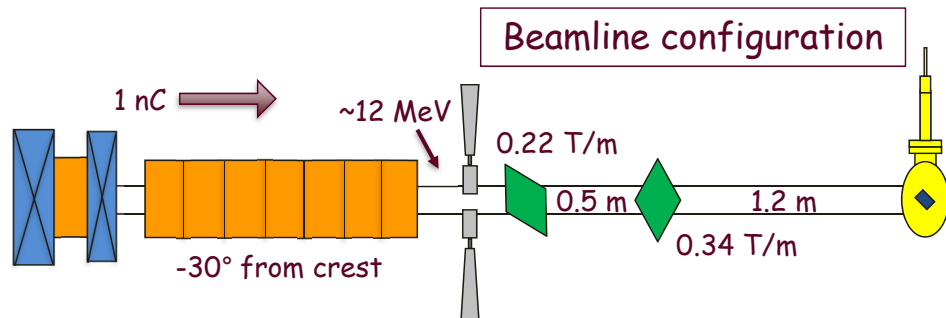
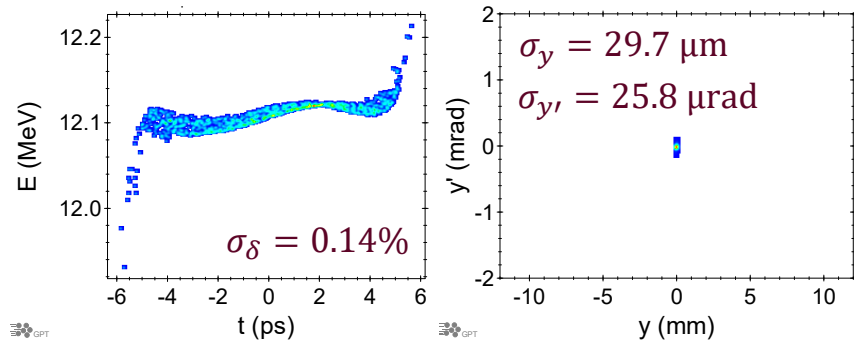


Horizontal phase space after slit

YAG image



Is it working with realistic beam?



Limiting factors

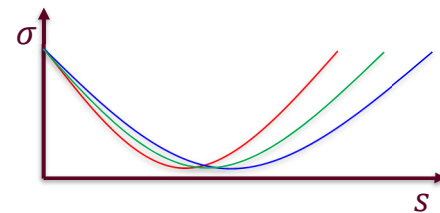


Limiting factors

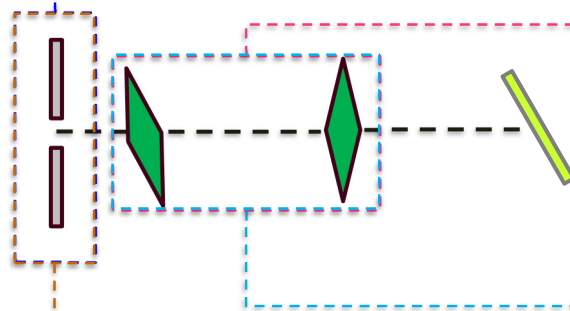
$$x_f = (D_2)x'_0 \pm \frac{D_2}{f}y_0$$

$$y_f = \pm \frac{2D + D_2}{f}x_0 + 2y_0 + (2D + D_2)y'_0$$

Remained extra transverse components
→ Gap size?



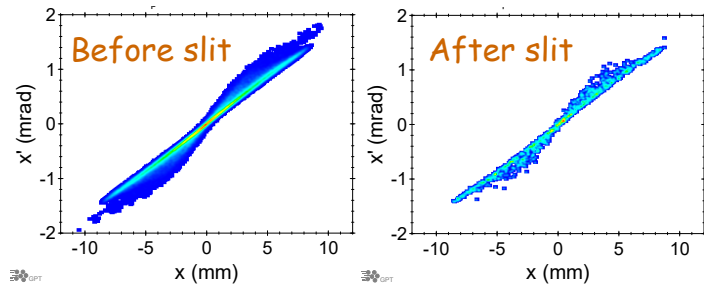
Chromatic effect due to energy spread



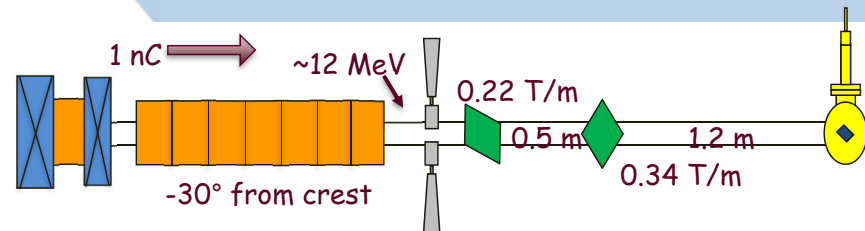
Quadrupole strength error

$$\begin{pmatrix} x_f \\ y_f \end{pmatrix} = \begin{pmatrix} 0 \rightarrow R'_{11} & R_{12} \rightarrow R'_{12} \\ R_{31} \rightarrow R'_{31} & R_{32} \rightarrow R'_{32} \end{pmatrix} \begin{pmatrix} x_0 \\ x'_0 \end{pmatrix}$$

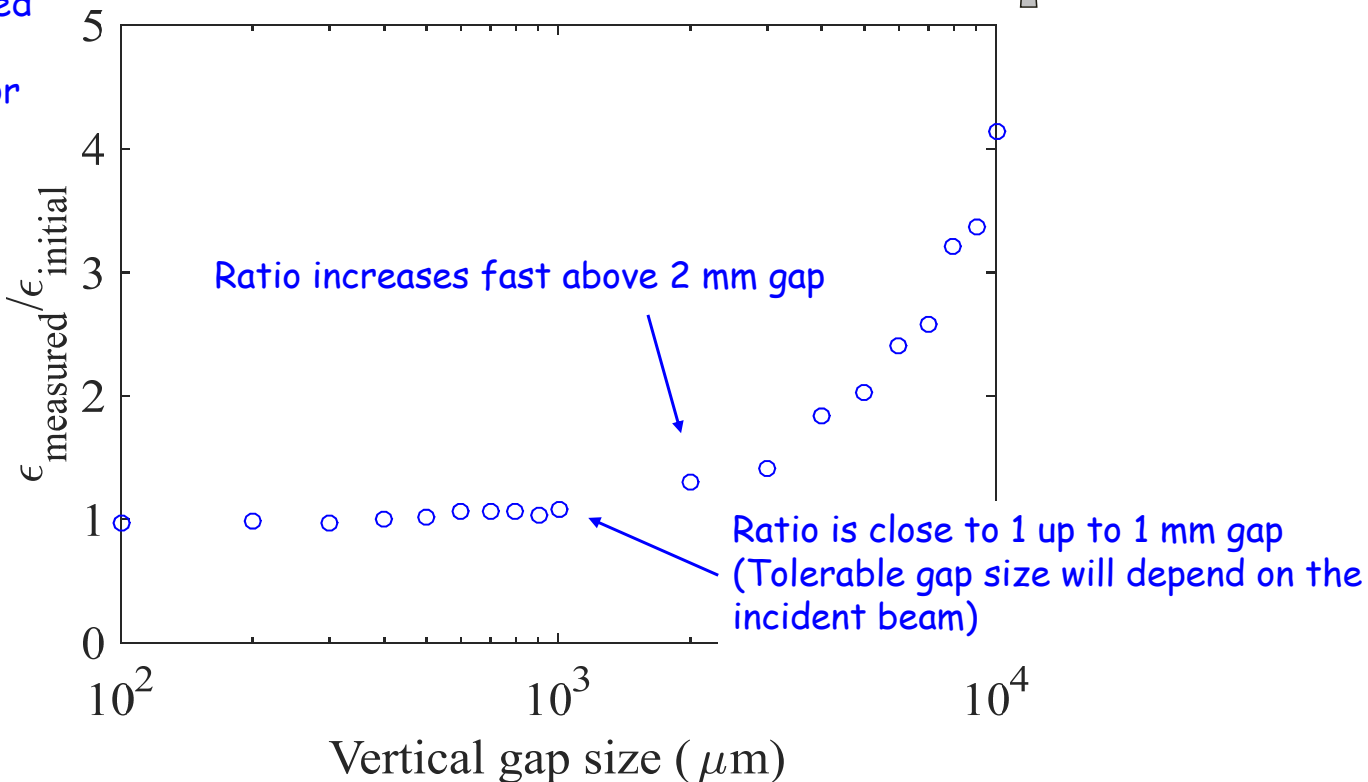
Beam selection from slit



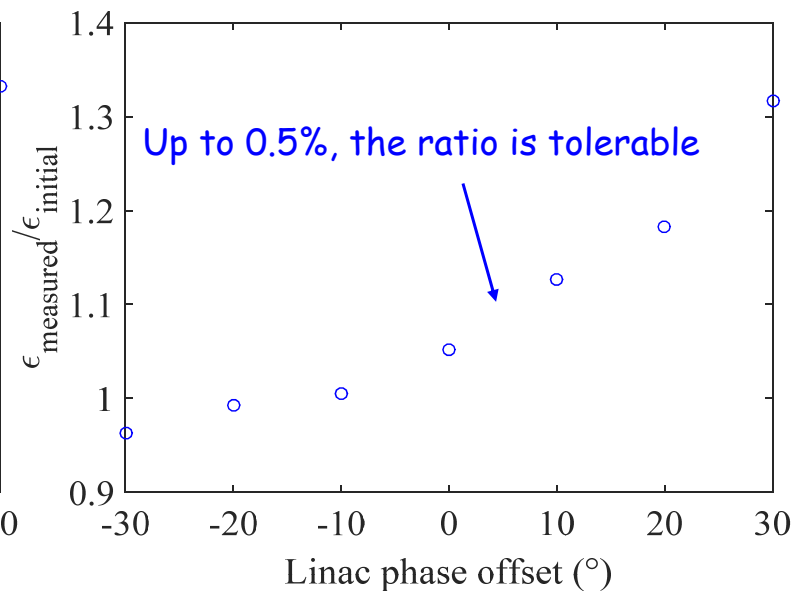
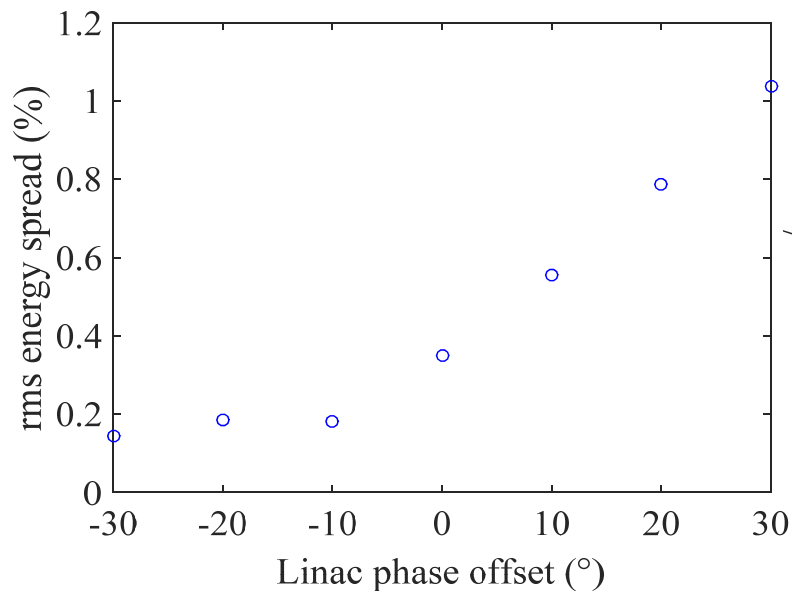
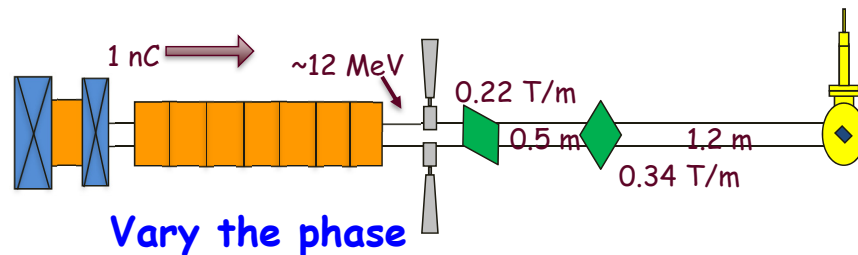
What gap size we can use?



Use the ratio of measured emittance to emittance after the slit as indicator

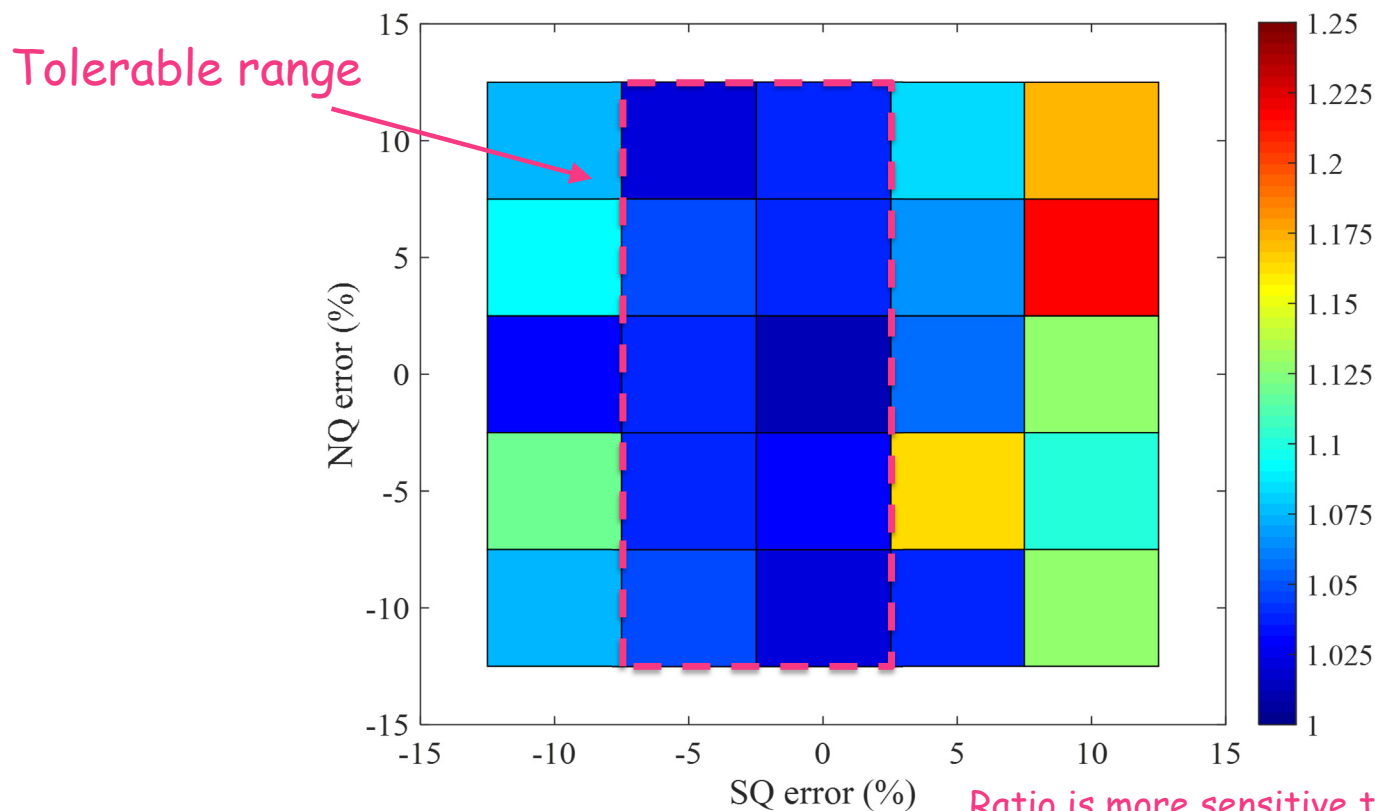


What energy spread we can tolerate?



What quadrupole error we can tolerate?

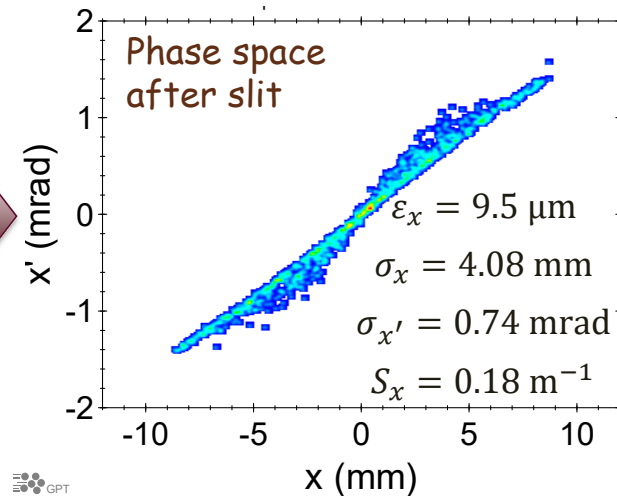
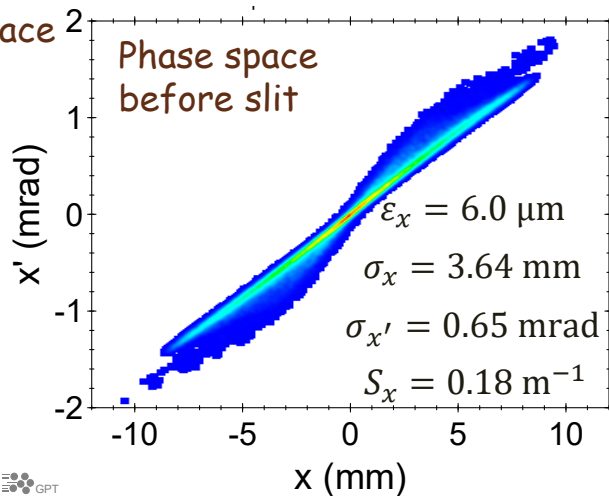
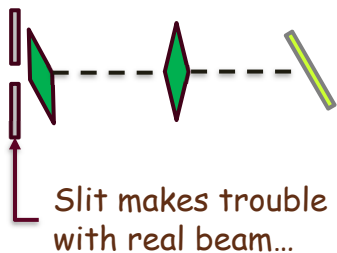
Colors are $\frac{\epsilon_{measure}}{\epsilon_{real}}$



Limitation of method...

*GPT S2E simulation result

Slit does not change the phase space if the beam is perfect Gaussian



Due to the slit...

- Beam loses more particle in the core than halo
- Beam size and divergence has error $\leq 10\%$
- Slope error is $\leq 1\%$ since the shape of phase space is preserved
- Emittance has error $\sim 50\%$

We are working on

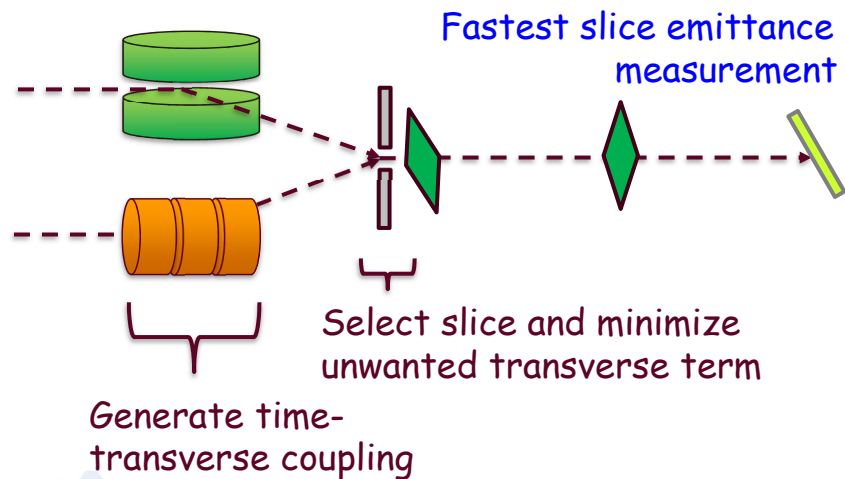
- *There should be way to retrieve the phase space from two or more averaged images without slit
- ** There should be way to minimize the vertical contribution without slit

Is this method still usable? YES



Application examples

- Alternative option of existing methods
- Slice emittance measurement
- Diagnose beam/beamline status
- Investigation of beam degradation source
- \vdots

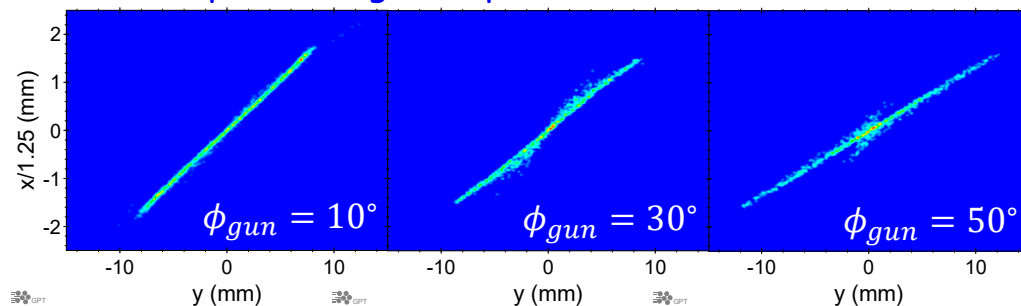


Alternative of existing methods

Full image	○	○	○
Data taking time	S	>	P < T
High-E availability	×	○	○
Space charge effect	S	~	P < T

S: slit-scan P: projection+scan T: tomography

Online space charge compensation

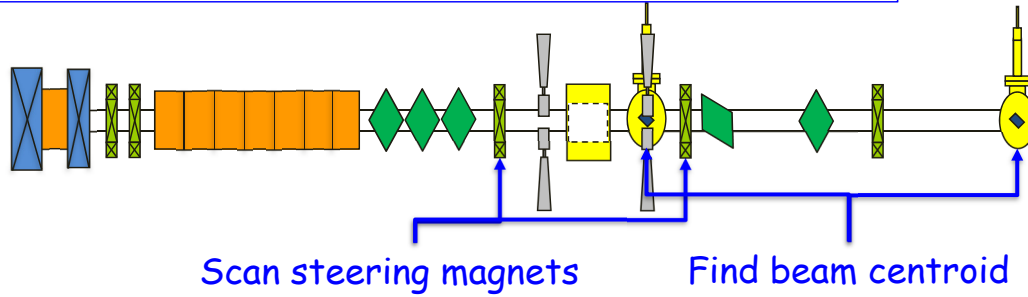


Experiment



Transport matrix measurement and inverse mapping

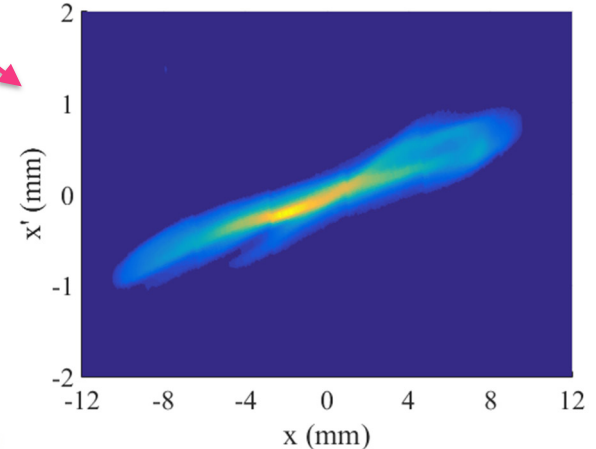
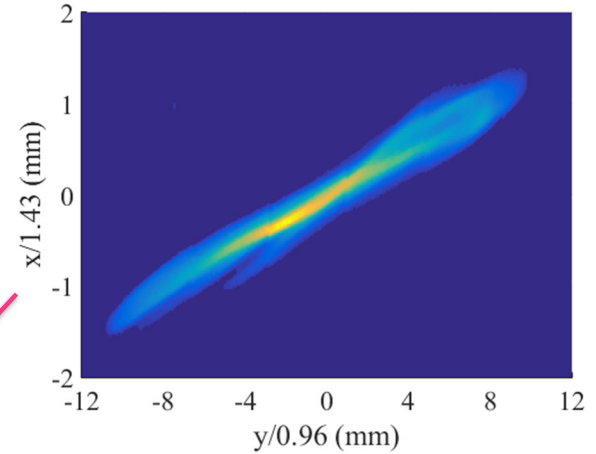
Argonne Wakefield Accelerator - Witness beamline



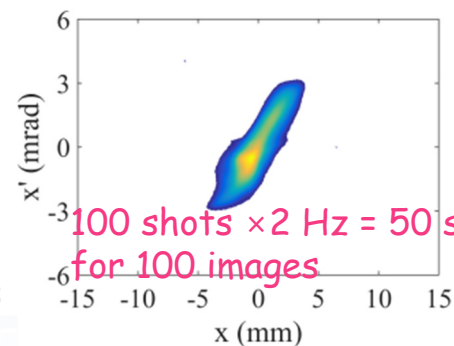
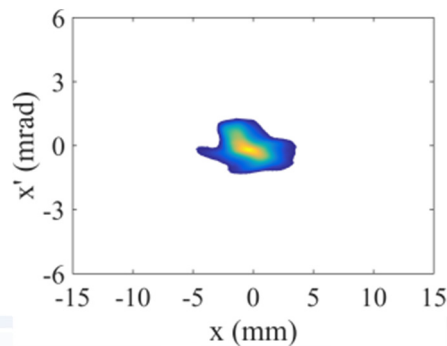
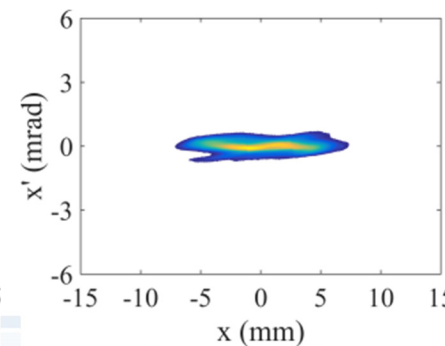
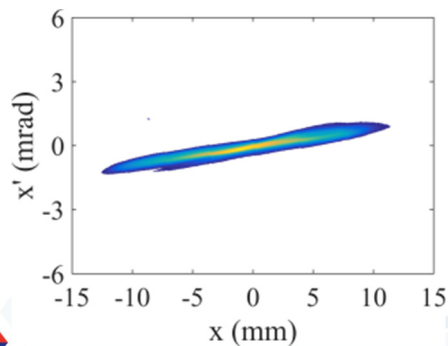
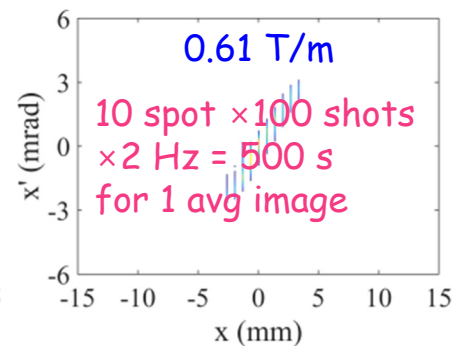
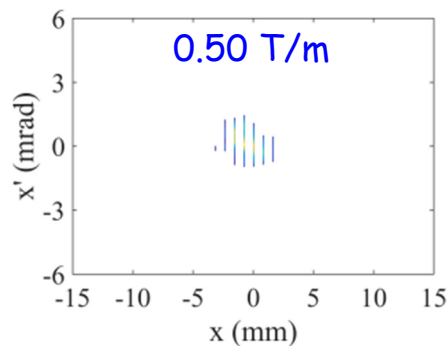
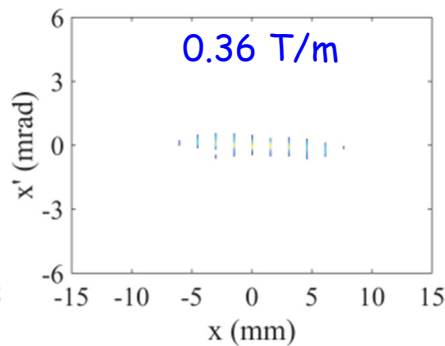
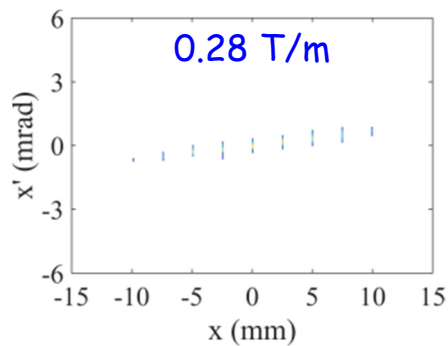
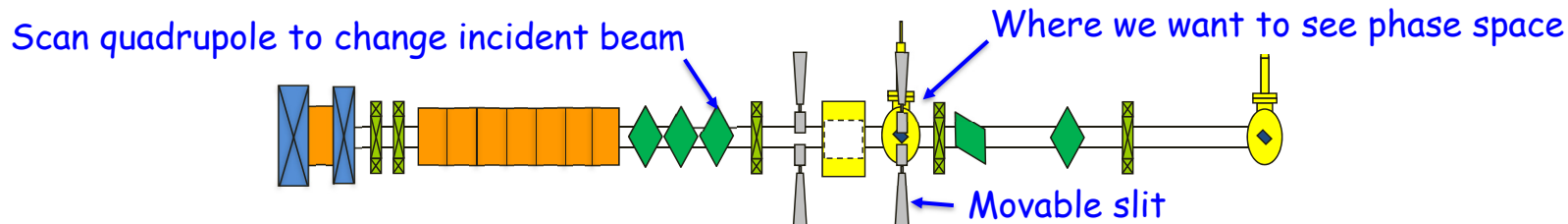
Coefficients of projection

	Designed	Measured
$C_{x_0 \rightarrow x_2}$	0.00	0.07 ± 0.05
$C_{x'_0 \rightarrow x_2}$	1.32	1.43 ± 0.06
$C_{x_0 \rightarrow y_2}$	1.04	0.96 ± 0.12
$C_{x'_0 \rightarrow y_2}$	0.33	0.31 ± 0.15

Need rotation too

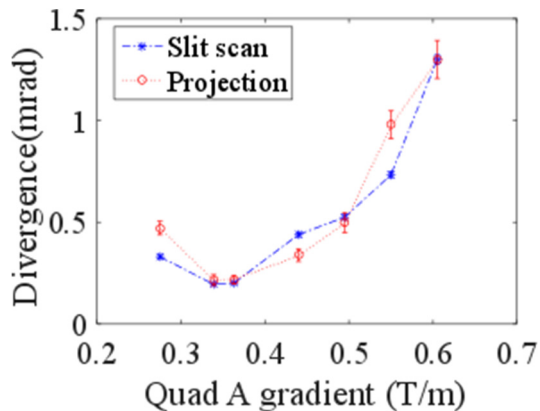
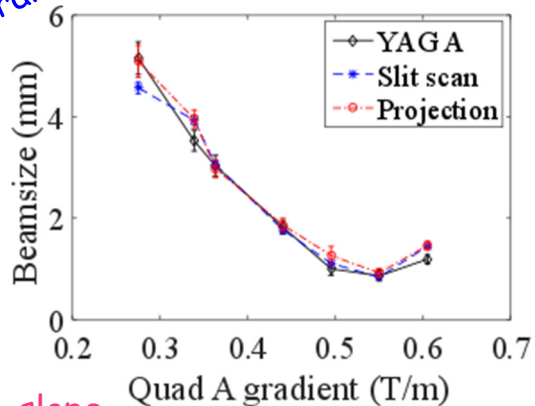


Comparison of slit scan and projection method

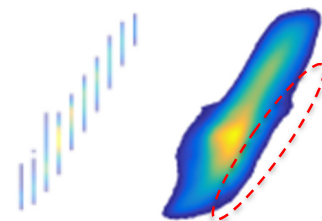


Comparison of slit scan and projection method

Beam statistical parameters



Due to charge density at screen

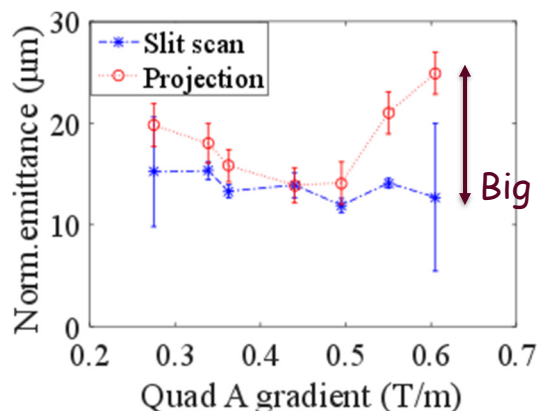
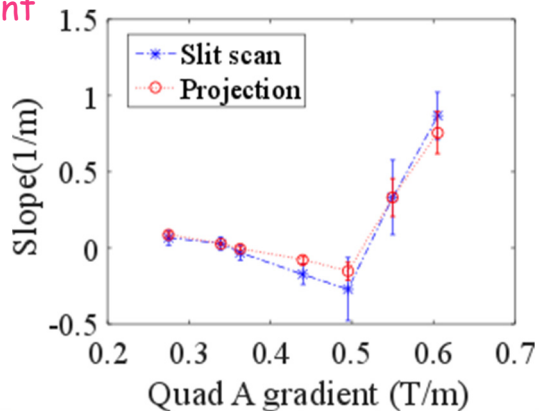


Slit-scan miss outer low density particles



Big difference on emittance

Beam size, divergence, slope shows good agreement



Conclusion

- The projection scheme is used to project transverse phase space to screen.
- The method is quite resistive to error sources (gap size, energy spread, strength).
- The method is not appropriate for emittance measurement due to the slit effect.
- The method has a limitation due to slit, but it can be applied many applications.
- The method is successfully demonstrated by comparison with slit-scan.
- AWA is working on finding advanced method to accurately calculate the emittance or phase space without slit.



Thank you for your attention